

**Notice of References Cited**

Application/Control No.

10/690,240

Applicant(s)/Patent Under  
Reexamination  
KUNO, OJI

Examiner

Cam N. Nguyen

Art Unit

1754

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0083194	05-2003	Sung, Shiang	502/304
*	B	US-7,052,777	05-2006	Brotzman et al.	428/570
*	C	US-6,645,439	11-2003	Zhang et al.	422/177
*	D	US-6,492,297	12-2002	Sung, Shiang	502/304
*	E	US-5,578,283	11-1996	Chen et al.	423/240R
*	F	US-5,491,120	02-1996	Voss et al.	502/304
*	G	US-5,283,041	02-1994	Nguyen et al.	423/240S
*	H	US-5,254,519	10-1993	Wan et al.	502/252
*	I	US-5,212,142	05-1993	Dettling, Joseph C.	502/304
*	J	US-6,911,414	06-2005	Kimura et al.	502/349
*	K	US-5,888,464	03-1999	Wu et al.	423/213.5
*	L	US-6,177,381	01-2001	Jensen et al.	502/325
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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